

# AUIRF2804STRL-VB Datasheet N-Channel 40 V (D-S) MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V)	$R_{DS(on)}$ ( $\Omega$ )	I <sub>D</sub> (A)	Q <sub>g</sub> (Typ.)	
40	0.0010 at V <sub>GS</sub> = 10 V	280	240 nC	
40	$0.0012$ at $V_{GS} = 4.5 \text{ V}$	250	240110	

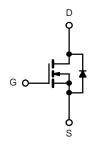
#### **FEATURES**

- Trench Power MOSFET
- 100 % R<sub>g</sub> and UIS Tested



#### **APPLICATIONS**

- Synchronous Rectification
- Power Supplies



N-Channel MOSFET

D <sup>2</sup> PAK	(TO-263)



ABSOLUTE MAXIMUM RATINGS	<b>S</b> T <sub>A</sub> = 25 °C, unle	ss otherwise not	ed		
Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	40	V	
Gate-Source Voltage		V <sub>GS</sub>	± 25	]	
Continuous Drain Current (T <sub>J</sub> = 175 °C)	T <sub>C</sub> = 25 °C		280		
	T <sub>C</sub> = 70 °C		220		
	T <sub>A</sub> = 25 °C	I <sub>D</sub>	229 <sup>b</sup>	A	
	T <sub>A</sub> = 70 °C		223 <sup>b</sup>	^	
Pulsed Drain Current		I <sub>DM</sub>	750		
Avalanche Current Pulse	L = 0.1 mH	I <sub>AS</sub>	80	7	
Single Pulse Avalanche Energy L = 0.1 mH		E <sub>AS</sub>	320	V	
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	I-	110 <sup>a, c</sup>	A	
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	2.6 <sup>b</sup>		
	T <sub>C</sub> = 25 °C		312 <sup>a</sup>		
Marian III Davida Disabatian	T <sub>C</sub> = 70 °C	P <sub>D</sub>	200	10/	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	r <sub>D</sub>	3.13 <sup>b</sup>	W	
	T <sub>A</sub> = 70 °C		2.0 <sup>b</sup>		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter	Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient <sup>b</sup>	Steady State	R <sub>thJA</sub>	32	40	°C/W	
Maximum Junction-to-Case	Steady State R <sub>thJC</sub> 0.33		0.33	0.4	C/VV	

#### Notes:

- a. Based on  $T_C = 25$  °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. Calculated based on maximum junction temperature. Package limitation current is 110  $\,\mathrm{A.}$



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	45			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	- I <sub>D</sub> = 250 μA		41		mV/°C
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			- 8		
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.2		2.5	V
Gate-Source Leakage	$I_{GSS}$	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zoro Coto Voltogo Drain Comment	1	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$			1	
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10	μΑ
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	120			Α
David Course Co. Otata Basista and	D	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 30 A		0.0010		Ω
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 4.5 \text{ V}, I_D = 20 \text{ A}$		0.0012		
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	$V_{DS} = 15 \text{ V}, I_{D} = 30 \text{ A}$		180		S
Dynamic <sup>b</sup>						
Input Capacitance	C <sub>iss</sub>			9335		pF
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		1150		
Reverse Transfer Capacitance	C <sub>rss</sub>			850		
Total Gate Charge	$Q_g$			160	260	nC
Gate-Source Charge	$Q_{gs}$	$V_{DS} = 20 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		40		
Gate-Drain Charge	Q <sub>gd</sub>			22		
Gate Resistance	$R_{g}$	f = 1 MHz		0.85	1.3	Ω
Turn-On Delay Time	t <sub>d(on)</sub>			20	30	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 20 V, $R_L$ = 1.0 $\Omega$		11	17	ns
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 20 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		77	115	
Fall Time	t <sub>f</sub>			10	15	
Turn-On Delay Time	t <sub>d(on)</sub>			102	155	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 20 V, $R_L$ = 1.0 $\Omega$		62	95	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 20 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		180	270	
Fall Time	t <sub>f</sub>			60	90	
<b>Drain-Source Body Diode Characteristic</b>	s					
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			110	۸
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				200	Α
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 20 A		0.8	1.2	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			50	75	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			70	105	nC
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		30		ns
Reverse Recovery Rise Time	t <sub>b</sub>			20		

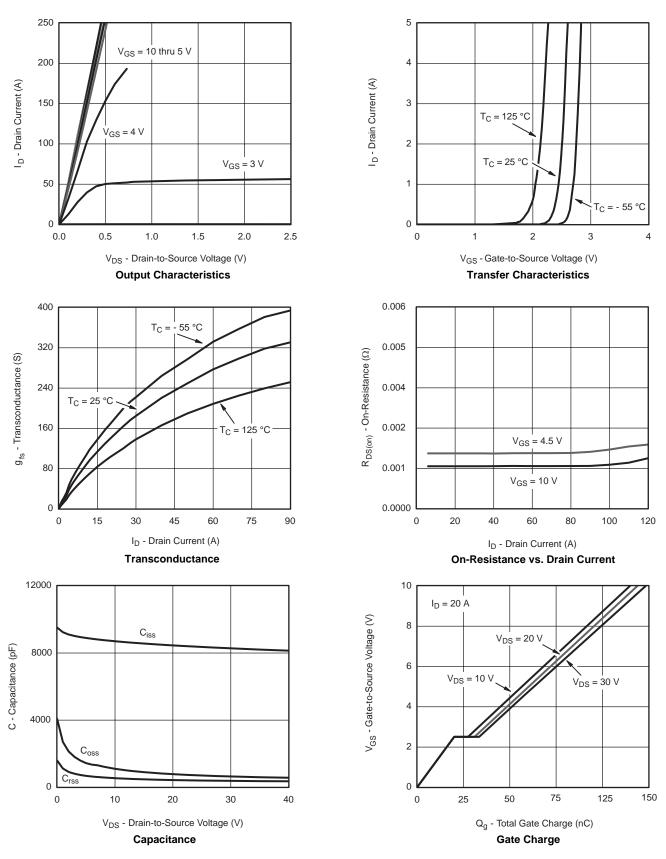
#### Notes:

- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

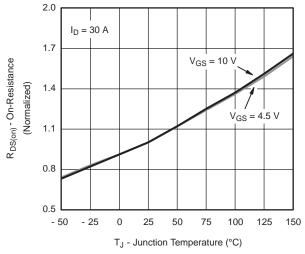


## TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

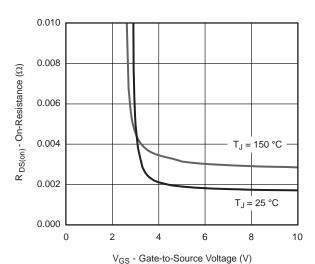




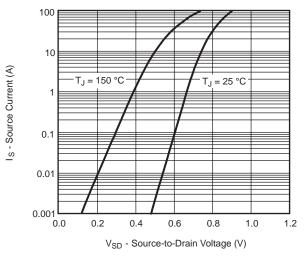
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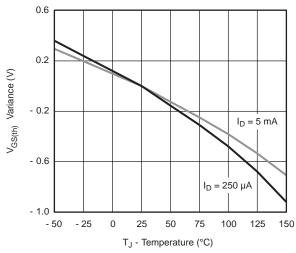
#### On-Resistance vs. Junction Temperature



On-Resistance vs. Gate-to-Source Voltage



#### Forward Diode Voltage vs. Temperature



Threshold Voltage

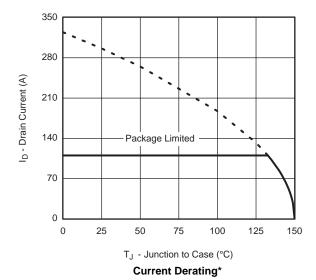


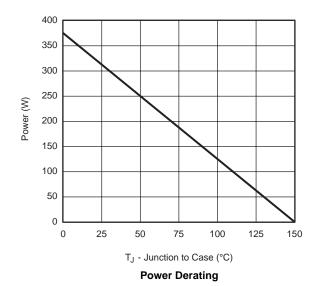
\*  $V_{GS}$  > minimum  $V_{GS}$  at which  $R_{DS(on)}$  is specified

Safe Operating Area, Junction-to-Ambient

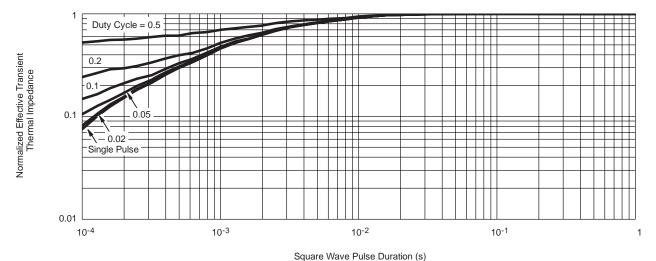


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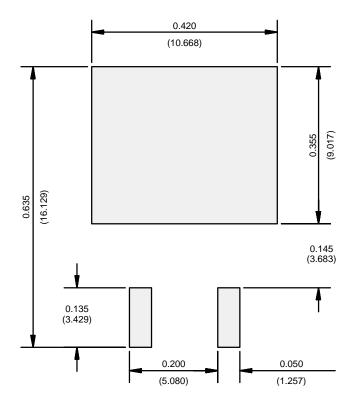
\* The power dissipation  $P_D$  is based on  $T_{J(max)}$  = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Normalized Thermal Transient Impedance, Junction-to-Case



### RECOMMENDED MINIMUM PADS FOR D2PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)



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